

## TPUL2G123-Q1 Automotive Dual RC-Timed Retriggerable Monostable Multivibrators

### 1 Features

- AEC-Q100 qualified for automotive applications:
  - Device temperature grade 1: -40°C to +125°C
  - Device HBM ESD classification level 2
  - Device CDM ESD classification level C4B
- RC configurable from 815ns to 883ms
- 1% typical, 10% maximum pulse width variation
- Wide operating range of 1.5V to 5.5V
- Inputs accept voltages up to 5.5V
- · Schmitt-trigger architecture on all inputs

### 2 Applications

- Demodulate a digital Amplitude Shift Keying (ASK) signal
- Reset a system for a fixed period of time
- · Generate a positive fixed-width digital pulse
- Detect a digital signal rising edge
- · Detect a digital signal falling edge
- Debounce a switch

### **3 Description**

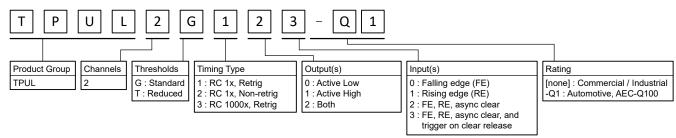
The TPUL2G123-Q1 device contains two independent RC configurable retriggerable monostable multivibrators designed for 1.5V to 5.5V operation. The output pulse duration is configured by selecting external resistance and capacitance values with an approximate output pulse width of  $t_{wo} \cong R \times C$ .

This device features three trigger inputs, allowing for rising edge (T) or falling edge ( $\overline{T}$ ) triggers and a clear input ( $\overline{CLR}$ ) that can be used asynchronously to stop an active output pulse. All trigger inputs include Schmitt-trigger architecture to allow for slow input transition rates and improve noise immunity.

**Device Information** 

PART NUMBER	PACKAGE (1)	PACKAGE SIZE <sup>(2)</sup>	BODY SIZE	
TPUL2G123-Q1	PW (TSSOP, 16)	5mm × 6.4mm	5 × 4.4mm	

- (1) For all available packages, see the orderable addendum at the end of the data sheet.
- (2) The package size (length × width) is a nominal value and includes pins, where applicable.



**TPUL family naming convention** 





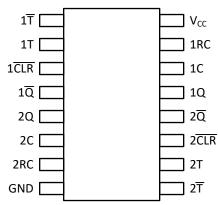
### **Table of Contents**

1 Features 2 Applications	1
3 Description	1
4 Pin Configuration and Functions	
5 Specifications	4
5.1 Absolute Maximum Ratings	4
5.2 ESD Ratings	4
5.3 Recommended Operating Conditions	4
5.4 Thermal Information	<mark>5</mark>
5.5 Electrical Characteristics	
5.6 Timing Characteristics	7
5.7 Switching Characteristics	<mark>8</mark>
5.8 Typical Characteristics	
6 Parameter Measurement Information	16
7 Detailed Description	17
7.1 Overview	
7.2 Functional Block Diagram	
7.3 Feature Description	
7.4 Device Functional Modes	

8 Application and Implementation	23
8.1 Application Information	
8.2 Typical Application - Edge Detector	
8.3 Typical Application - Delayed Pulse Generator	
8.4 Power Supply Recommendations	
8.5 Layout	. 28
9 Device and Documentation Support	
9.1 Documentation Support.	
9.2 Receiving Notification of Documentation Updates	
9.3 Support Resources	. 29
9.4 Trademarks	29
9.5 Electrostatic Discharge Caution	29
9.6 Glossary	29
10 Revision History	
11 Mechanical, Packaging, and Orderable	
Information	. 29
11.1 Packaging Option Addendum	. 30
11.2 Tape and Reel Information	
11.3 Mechanical Data	



### **4** Pin Configuration and Functions



See mechanical drawings for dimensions.

#### Figure 4-1. PW Package 16-Pin TSSOP Top View

#### Table 4-1. Pin Functions

PIN		I/O <sup>(1)</sup>	DESCRIPTION		
NAME	NO.	1/0(*/	DESCRIPTION		
1₸	1	I	Channel 1 falling edge trigger input; requires 1T and 1CLR to be held high		
1T	2	I	Channel 1 rising edge trigger input; requires $1\overline{T}$ to be held low and $1\overline{CLR}$ to be held high		
1CLR	3	I	Channel 1 asynchronous clear input, active low; also can operate as rising edge trigger input if $1\overline{T}$ is held low and $1T$ is held high		
1Q	4	0	Channel 1 inverted output		
2Q	5	0	Channel 2 output		
2C	6	G	Channel 2 external timing capacitor negative connection; provides a return path for discharge current of the external timing capacitor; internally connected to ground		
2RC	7	I/O	Channel 2 external timing node connection; see <i>Application Information</i> section for detailed operation instructions		
GND	8	G	Ground		
2 <b>T</b>	9	I	Channel 2 falling edge trigger input; requires 2T and 2CLR to be held high		
2T	10	I	Channel 2 rising edge trigger input; requires $2\overline{T}$ to be held low and $2\overline{CLR}$ to be held high		
2 <del>CLR</del>	11	I	Channel 2 asynchronous clear input, active low; also can operate as rising edge trigger input if $2\overline{T}$ is held low and 2T is held high		
2Q	12	0	Channel 2 inverted output		
1Q	13	0	Channel 1 output		
1C	14	G	Channel 1 external timing capacitor negative connection; provides a return path for discharge current of the external timing capacitor; internally connected to ground		
1RC	15	I/O	Channel 1 external timing node connection; see <i>Application Information</i> section for detailed operation instructions		
V <sub>CC</sub>	16	Р	Postive voltage supply		

(1) I = Input, O = Output, I/O = Input and output, G = Ground, P = Power



### **5** Specifications

#### 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	6.5	V
VI	Digital input voltage range <sup>(2)</sup>		-0.5	6.5	V
Vo	Digital output voltage range in the active state <sup>(2)</sup>		-0.5	V <sub>CC</sub> + 0.5	V
Vo	Digital output voltage range in the high-impedance state <sup>(2)</sup>		-0.5	6.5	V
V <sub>RC</sub>	RC pin voltage range		-0.5	V <sub>CC</sub> + 0.5	V
	Input clamp diode current, continuous	V <sub>I</sub> < -0.5V		-20	mA
I <sub>IK</sub>	Input clamp diode current, pulsed 1µs	V <sub>I</sub> < -0.5V		-200	mA
	Output clamp diode current, continuous	V <sub>O</sub> < -0.5V		-20	mA
I <sub>OK</sub>	Output clamp diode current, pulsed 1µs	V <sub>O</sub> < -0.5V		-200	mA
	Digital output current, continuous	$V_{O} = 0$ to $V_{CC}$		±50	mA
I <sub>O</sub>	Digital output current, pulsed 1µs	$V_{O} = 0$ to $V_{CC}$		±200	mA
	Continuous current through $V_{CC}$ or GND			±200	mA
R <sub>ext</sub>	External timing resistance		1		kΩ
C <sub>ext</sub>	External timing capacitance			1 <sup>(3)</sup>	μF
TJ	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature		-65	150	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) The voltage ratings may be exceeded if the associated clamp current ratings are observed.

(3) The timing capacitance maximum value can be exceeded if an external diode is added. See *Application and Implementation* section for details.

### 5.2 ESD Ratings

			VALUE	UNIT
	Electrostatic	Human body model (HBM), per AEC Q100-002 HBM ESD Classification Level 2 <sup>(1)</sup>	±2000	
V <sub>(ESD)</sub>	discharge	Charged device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	±1000	V

(1) AEC Q100-002 indicate that HBM stressing shall be in accordrance with the ANSI/ESDA/JEDEC JS-001 specification.

### **5.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)

Spec	Description	Condition	MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		1.5	5.5	V
VI	Input Voltage <sup>(1)</sup>		0	5.5	V
Vo	Output Voltage	0	V <sub>CC</sub>	V	
	High-level output current	V <sub>CC</sub> = 1.5V		-4	mA
		V <sub>CC</sub> = 1.8V		6	mA
I <sub>OH</sub> <sup>(3)</sup>		V <sub>CC</sub> = 2.5V		-26	mA
		V <sub>CC</sub> = 3.3V		-50	mA
		V <sub>CC</sub> = 5V		-50	mA

#### over operating free-air temperature range (unless otherwise noted)

Spec	Description	Condition	MIN	MAX	UNIT
		V <sub>CC</sub> = 1.5V		4	mA
		V <sub>CC</sub> = 1.8V		6	mA
I <sub>OL</sub> <sup>(3)</sup>	Low-level output current	V <sub>CC</sub> = 2.5V		26	mA
		V <sub>CC</sub> = 3.3V		50	mA
		V <sub>CC</sub> = 5V		50	mA
R <sub>ext</sub> <sup>(2)</sup>	External timing resistance	V <sub>CC</sub> = 1.5V to 5.5V	6.5	1000	kΩ
C <sub>ext</sub> <sup>(2)</sup>	External timing capacitance	V <sub>CC</sub> = 1.5V to 5.5V	0.1	1000	nF
t <sub>wo</sub>	Configured output pulse width	V <sub>CC</sub> = 1.5V to 5.5V	0.001	860	ms
CL	Digital output load capacitance	V <sub>CC</sub> = 1.5V to 5.5V		50	pF
V <sub>POR</sub>	Power-on reset ramp voltage	$\Delta t / \Delta V_{CC} = 20 \mu s / V$ to 100ms / V	0.3	1.5	V
$\Delta t / \Delta V_{CC}$	Power-on ramp rate	V <sub>CC</sub> = 0.3V to 1.5V	20	100000	μs/V
Δt/Δv	Input transition rise or fall rate	V <sub>CC</sub> = 1.5V to 5.5V		100	ms/V
T <sub>A</sub>	Operating free-air temperature	Operating free-air temperature	-40	125	°C

(1) All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation.

(2) Recommended  $R_{ext}$  and  $C_{ext}$  values maintain maximum error provided as  $\Delta t_{wo}$  in the Switching Characteristics table.

(3) Recommended maximum output current for continuous operation; see *Electrical Characteristics* for test current values to maintain V<sub>OH</sub> and V<sub>OL</sub> specifications.

### **5.4 Thermal Information**

PACKAGE	PINS	THERMAL METRIC <sup>(1)</sup>						UNIT
PACKAGE	FING	R <sub>0JA</sub>	R <sub>0JC(top)</sub>	R <sub>θJB</sub>	$\Psi_{JT}$	$\Psi_{JB}$	R <sub>θJC(bot)</sub>	UNIT
PW (TSSOP)	16	138.3	75.1	96.5	19.4	95.5	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application note.

### **5.5 Electrical Characteristics**

Over operating free-air temperature range; typical values measured at T<sub>A</sub> = 25°C (unless otherwise noted)

PA	RAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
			1.5V	0.75	0.90	0.99	
			1.8V	0.86	1.03	1.17	
	Positive		2.5V	1.1	1.29	1.47	V
V <sub>T+</sub>	switching threshold		3.3V	1.37	1.56	1.76	v
			5V	1.92	2.16	2.4	
			5.5V	2.08	2.33	2.6	
			1.5V	0.41	0.47	0.54	
			1.8V	0.48	0.53	0.6	
V <sub>T-</sub>	Negative		2.5V	0.63	0.69	0.76	V
	switching threshold		3.3V	0.8	0.87	0.96	v
			5V	1.13	1.25	1.39	
			5.5V	1.22	1.36	1.51	

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Uver operating tree-air temperature range. Typical values measured at 1	$_{1} = 25^{\circ}()$ (Unless otherwise noted)
Over operating free-air temperature range; typical values measured at T	

P	ARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	ТҮР	MAX	UNIT
			1.5V	0.34	0.45	0.6	
			1.8V	0.38	0.5	0.66	
A. \ /	Hysteresis		2.5V	0.47	0.6	0.78	V
ΔV <sub>T</sub>	(V <sub>T+</sub> - V <sub>T-</sub> )		3.3V	0.56	0.69	0.89	V
			5V	0.77	0.9	1.12	
			5.5V	0.83	0.96	1.2	
		Ι <sub>ΟΗ</sub> = -50μΑ	1.5V - 5.5V	V <sub>CC</sub> - 0.1	V <sub>CC</sub> - 0.01		
		I <sub>OH</sub> = -1mA	1.65V	1.2	1.61		
,	High-level	I <sub>OH</sub> = -2mA	2.3V	2.1	2.24		V
/ <sub>ОН</sub>	output voltage	I <sub>OH</sub> = -8mA	3V	2.4	2.78		V
		I <sub>OH</sub> = -12mA	4.5V	3.94	4.21		
		I <sub>OH</sub> = -12mA	5.5V	4.94	5.23		
		I <sub>OL</sub> = 50μA	1.5V - 5.5V		0.01	0.1	
		I <sub>OL</sub> = 1mA	1.65V		0.03	0.45	
	Low-level	I <sub>OL</sub> = 2mA	2.3V		0.04	0.2	.,
V <sub>OL</sub>	output voltage	I <sub>OL</sub> = 8mA	3V		0.13	0.4	V
	I <sub>OL</sub> = 12mA	4.5V		0.15	0.5		
		I <sub>OL</sub> = 12mA	5.5V		0.13	0.5	
1	Input leakage current	V <sub>I</sub> = 5.5V or 0V	0V to 5.5V			±50	nA
CEXT	Capacitor pin current	Monitor state, $V_{CEXT} = 0.5 \times V_{CC}$	1.5V to 5.5V			±50	nA
		Active state, discharging, V <sub>CEXT</sub> = 1.5V	1.5V			11	mA
		Active state, discharging, V <sub>CEXT</sub> = 2.3V	2.3V			29	mA
CEXT	Capacitor pin current	Active state, discharging, V <sub>CEXT</sub> = 3V	3V			45	mA
	Current	Active state, discharging, V <sub>CEXT</sub> = 4.5V	4.5V			95	mA
		Active state, discharging, V <sub>CEXT</sub> = 5.5V	5.5V			138	mA
off	Partial power- off current	$V_{\rm I}$ or $V_{\rm O}$ = 5.5V or 0V	0V to 0.3V		0.25	10	μA
СС	Supply current	Ready state, $V_I = V_{CC}$ or 0V, $I_O = 0$	5.5V		0.19	2	μA
			1.5V			40	
			1.65V			50	
			2.3V			75	
СС	Supply current	Active state per channel, $V_I = V_{CC}$ or 0V, $I_O = 0$	3V			100	μA
			4.5V			155	
			5.5V			195	
۵l <sup>cc</sup>	Supply-current change	One input, $V_i = 0$ to $V_{CC}$ , all other inputs at $V_{CC}$ or 0V, $I_O = 0$ mA	1.5V to 5.5V			1.5	mA
CI	Input capacitance	V <sub>I</sub> = 5.5V or 0V	5.5V		1		pF
Co	Output capacitance	V <sub>O</sub> = 5.5V or 0V	0V		3		pF
Co		V <sub>O</sub> = 5.5V or 0V	0V		3		



Over operating free-air temperature range; typical values measured at  $T_A = 25^{\circ}C$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
			1.5V	16	17.9	20	
C <sub>int</sub> Internal capacitance		1.65V	14	15.5	17		
	Internal	$C_{ext} = 0pF; V_{cext} = 0 \text{ to } V_{CC}$	2.3V	7	9.7	13	pF
	capacitance		3V	6	9.9	14	
			4.5V	5	7.7	10	
			5.5V	4	5.7	7	

### **5.6 Timing Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

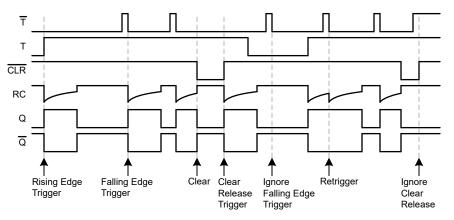
PARAMETER	DESCRIPTION	CONDITION	V <sub>cc</sub>	MIN MAX	UNIT
			1.5V	18.2	
			1.8V ± 0.15V	9.9	1
t <sub>wi</sub>	Pulse duration	Any trigger input	2.5V ± 0.2V	7.8	ns
			3.3V ± 0.3V	5.8	1
			5V ± 0.5V	4.1	1
			1.5V	9.6	
			1.8V ± 0.15V	8	1
		$\overline{T}$ low before $T\!\!\uparrow$ or $\overline{CLR}\!\!\uparrow$	2.5V ± 0.2V	6.9	ns
			3.3V ± 0.3V	6.6	1
			5V ± 0.5V	6.5	]
			1.5V	5	
	Setup time between trigger inputs		1.8V ± 0.15V	5	ns
t <sub>su</sub>		T high before $\overline{T}_{\downarrow}$ or $\overline{CLR}_{\uparrow}$	2.5V ± 0.2V	5	
			3.3V ± 0.3V	5	]
			5V ± 0.5V	5	
			1.5V	9.2	-
			1.8V ± 0.15V	7.8	
		$\overline{\text{CLR}}$ high before $\overline{T}_{\downarrow}$ or $T_{\uparrow}$	2.5V ± 0.2V	6.7	ns
			3.3V ± 0.3V	6.5	1
			5V ± 0.5V	6.4	1
			1.5V	9.3	
			1.8V ± 0.15V	7.8	ns
t <sub>h</sub>	Hold time	Any trigger input	2.5V ± 0.2V	6.7	
			3.3V ± 0.3V	6.5	
			5V ± 0.5V	6.4	1

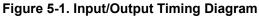
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#### over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	DESCRIPTION	CONDITION	V <sub>cc</sub>	MIN	MAX	UNIT
			1.5V	72	240	
			1.8V ± 0.15V	63	184	
		Any trigger input, C <sub>ext</sub> = 100pF	2.5V ± 0.2V	41	93	ns
			3.3V ± 0.3V	30	66	
			5V ± 0.5V	22	46	
			1.5V	12	54	
			1.8V ± 0.15V	11	44	
t <sub>rr</sub>	Retrigger time	Any trigger input, C <sub>ext</sub> = 0.1µF	2.5V ± 0.2V	7.7	26	
			3.3V ± 0.3V	6.6	20	
			5V ± 0.5V	5.5	15	
			1.5V	1.2	5.4	
			1.8V ± 0.15V	1	4.3	
		Any trigger input, C <sub>ext</sub> = 10μF	2.5V ± 0.2V	0.7	2.5	ms
			3.3V ± 0.3V	0.6	1.9	
			5V ± 0.5V	0.5	1.4	
t <sub>startup</sub> <sup>(1)</sup>	Startup time		1.5V to 5.5V		200	μs

(1) Triggers are ignored during startup time





### 5.7 Switching Characteristics

over operating free-air temperature range; typical values measured at  $T_A = 25^{\circ}C$  (unless otherwise noted). See *Parameter Measurement Information*.

PARAME TER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V <sub>cc</sub>	MIN	ТҮР	МАХ	UNIT				
C <sub>L</sub> = 15pF												
				1.5V	13	28.6	64	ns				
				1.65V	10	23.1	51	ns				
	$\overline{T}$ , T, or $\overline{CLR}$	0		2.3V	6	13.7	28	ns				
t <sub>pd</sub>		Q or Q	C <sub>L</sub> = 15pF	3V	5	9.8	20	ns				
				4.5V	3	7.1	14	ns				
				5.5V	3	6.3	13	ns				



over operating free-air temperature range; typical values measured at T<sub>A</sub> = 25°C (unless otherwise noted). See *Parameter Measurement Information*.

PARAME TER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V <sub>cc</sub>	MIN	ТҮР	МАХ	UNIT
				1.5V		4.3	8.3	ns
				1.65V		3.9	7	ns
t.		Q or $\overline{Q}$	C <sub>L</sub> = 15pF	2.3V		3	5.6	ns
tt				3V		2.5	5	ns
				4.5V		2.4	4.9	ns
				5.5V		2.7	5.8	ns
C <sub>L</sub> = 50pF								
				1.5V	13	31.8	72	ns
				1.65V	10	24.8	57	ns
+	$\overline{T}$ , T, or $\overline{CLR}$	Q or $\overline{Q}$	C = 50 pc	2.3V	6	14.3	32	ns
t <sub>pd</sub>			C <sub>L</sub> = 50pF	3V	5	10.8	23	ns
				4.5V	3	7.9	16	ns
				5.5V	3	7	14	ns
				1.5V	135	223	405	ns
				1.65V	123	185	311	ns
			$R_{ext} = 10k\Omega; C_{ext} = 0;$	2.3V	96	117	161	ns
			$R_{ext}$ = 10kΩ; $C_{ext}$ = 0; $C_L$ = 50pF	3V	82	95	118	ns
				4.5V	68	75	96	ns
(1)				5.5V	64	69	88	ns
t <sub>wo</sub> (1)		$Q \text{ or } \overline{Q}$		1.5V	814	905	996	μs
				1.65V	815	906	997	μs
			$R_{ext} = 10k\Omega; C_{ext} =$	2.3V	815	906	997	μs
			$0.1\mu$ F; C <sub>L</sub> = 50pF	3V	815	906	997	μs
				4.5V	805	895	985	μs
				5.5V	793	882	971	μs
∆t <sub>wo</sub> (2)		Q or $\overline{Q}$	C <sub>L</sub> = 50pF	1.5V to 5.5V		±5	±10	%
				1.5V		8.2	34.4	ns
				1.65V		7	28	ns
				2.3V		4.5	24.6	ns
tt		Q or $\overline{Q}$	C <sub>L</sub> = 50pF	3V		3.9	17.4	ns
				4.5V		3.1	12.6	ns
				5.5V		2.9	8.7	ns
				1.5V		42		pF
			=	1.65V		41		pF
- (0)			$T = V_{CC}, \overline{T} = GND, f_{I}$ $= 10MHz, C_{L} = 50pF,$	2.3V		40		pF
C <sub>pd</sub> <sup>(3)</sup>	CLR		C <sub>ext</sub> = 0pF, R <sub>ext</sub> =	3V		32		pF
			1ΜΩ	4.5V		35		pF
			4.5V 5.5V			38		pF

(1) Output pulse width

(2) Variation in output pulse width as compared to typical characteristics for K factor excluding variations in external timing components. Only applies within recommended operating conditions.

(3) Power dissipation capacitance is calculated in accordance with CMOS Power Consumption and Cpd Calculation.



### **5.8 Typical Characteristics**

 $T_A = 25^{\circ}C$  (unless otherwise noted)

#### Note

The TPUL family of devices are in early release. Preliminary data is provided.

		Table 5-1.	Pulse width u	ising commo	on RC, V <sub>CC</sub> = 3	3.3V	
Resistor Value	Capacitor V	alue					
	10µF	1µF	100nF	10nF	1nF	100pF	10pF
1kΩ	9.51ms	951µs	99.5µs	10.3µs	1.14µs	168ns	58.1ns
1.5kΩ	14.1ms	1.41ms	1.44µs	14.9µs	1.63µs	227ns	65.2ns
2.2kΩ	20.4ms	2.04ms	207µs	21.3µs	2.34µs	311ns	79.5ns
3.3kΩ	30.1ms	3.01ms	306µs	31.5µs	3.42µs	439ns	96.2ns
4.7kΩ	42.5ms	4.25ms	432µs	44.3µs	4.83µs	604ns	117ns
6.8kΩ	61.2ms	6.12ms	621µs	63.9µs	6.91µs	849ns	147ns
10kΩ	89.3ms	8.93ms	907µs	93.4µs	10.1µs	1.22µs	194ns
15kΩ	134ms	13.4ms	1.35ms	140µs	15.1µs	1.80µs	264ns
22kΩ	196ms	19.6ms	1.99ms	205µs	22.0µs	2.62µs	363ns
33kΩ	294ms	29.4ms	2.97ms	307µs	33.1µs	3.89µs	518ns
47kΩ	417ms	41.7ms	4.23ms	436µs	46.8µs	5.52µs	716ns
68kΩ	605ms	60.5ms	6.12ms	629µs	67.9µs	7.95µs	1.00µs
100kΩ	888ms	88.8ms	9.00ms	925µs	100µs	11.7µs	1.46µs
150kΩ	1.33s	133ms	13.46ms	1.39ms	150µs	17.4µs	2.15µs
220kΩ	1.95s	195ms	19.75ms	2.04ms	220µs	25.6µs	3.12µs
330kΩ	2.93s	293ms	29.62ms	3.05ms	330µs	38.1µs	4.64µs
470kΩ	4.17s	417ms	42.15ms	4.36ms	470µs	54.5µs	6.59µs
680kΩ	6.04s	604ms	60.97ms	6.28ms	680µs	79.2µs	9.50µs
1MΩ	8.83s	883ms	89.95ms	9.28ms	1ms	117µs	13.9µs

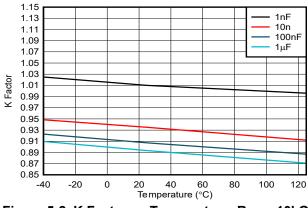
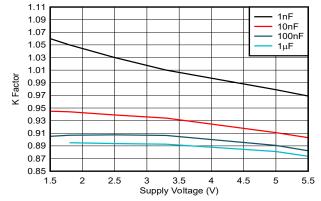
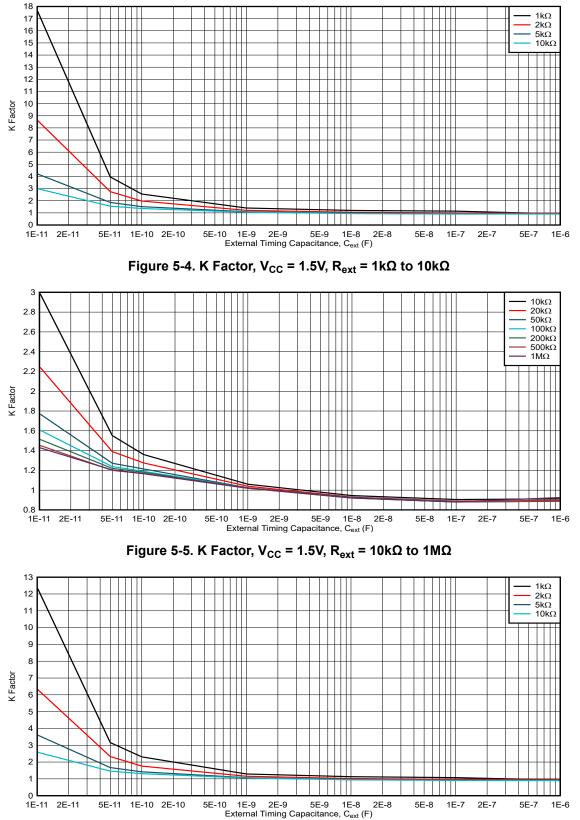


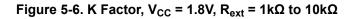
Figure 5-2. K Factor vs Temperature,  $R_{ext} = 10k\Omega$ 

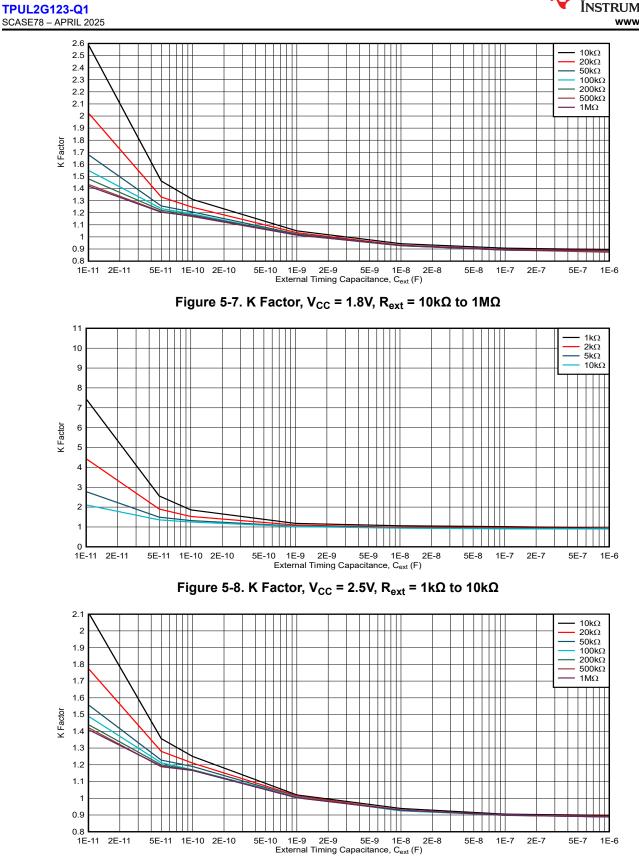


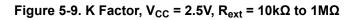




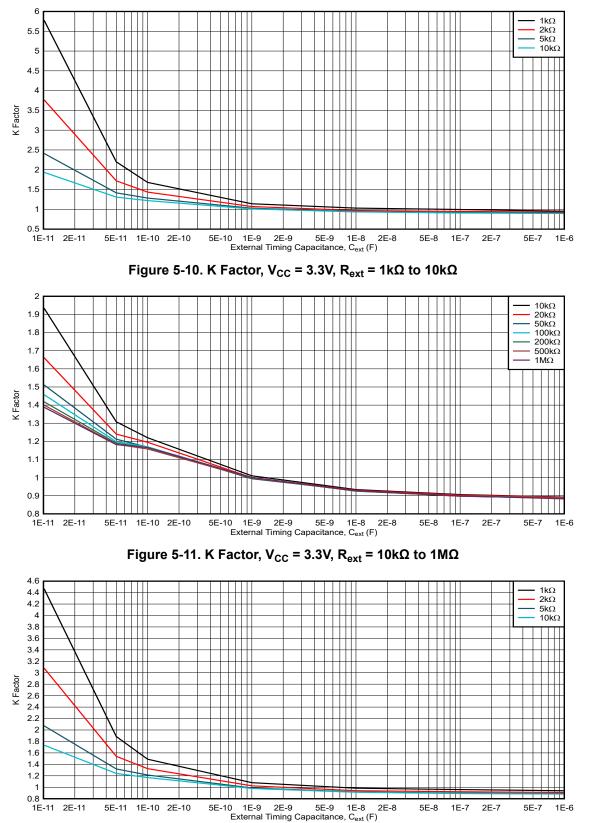


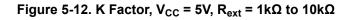


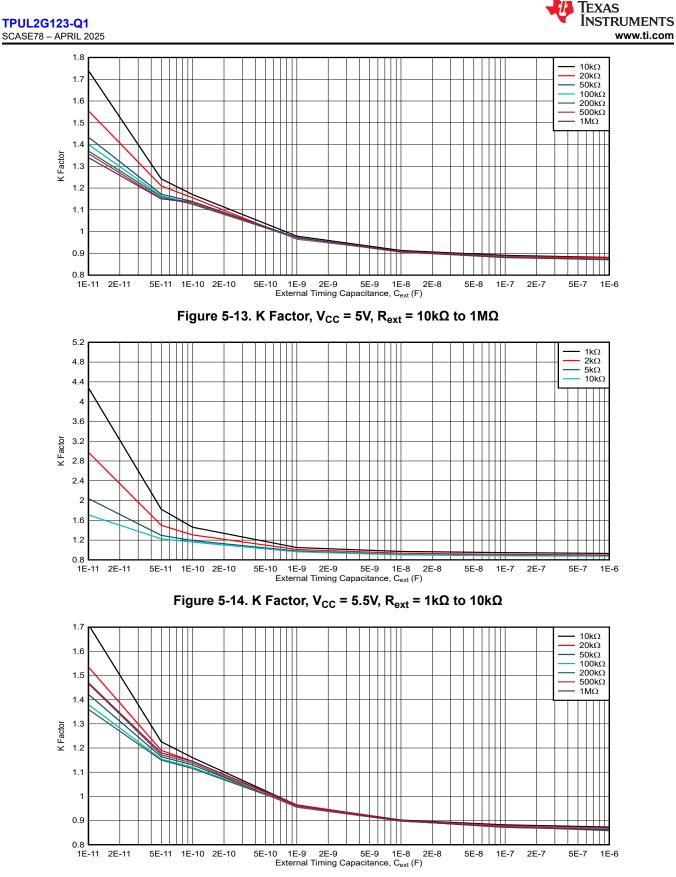


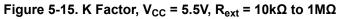






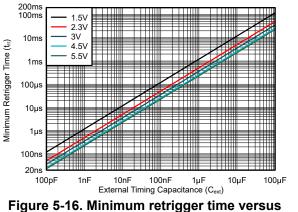








**TPUL2G123-Q1** SCASE78 - APRIL 2025



external timing capacitor value

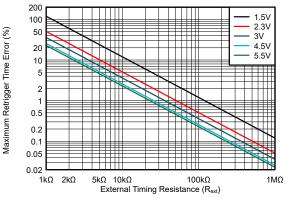


Figure 5-17. Maximum retrigger time error as a percentage of total pulse width versus external timing resistor value

Error data in the following plots indicates changes from typical behavior (nominal material,  $T_A = 25^{\circ}C$ ) due to variation in manufacturing process and operating free-air temperature.

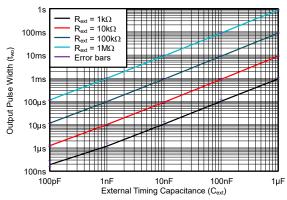


Figure 5-18. Typical output pulse width versus timing capacitance value with error bar overlay

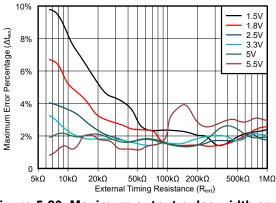


Figure 5-20. Maximum output pulse width error (absolute value) versus timing resistor values with (absolute value) versus timing resistor values with C<sub>ext</sub> = 100pF

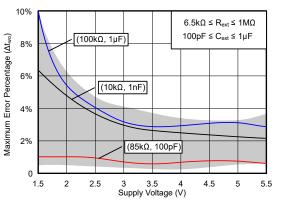
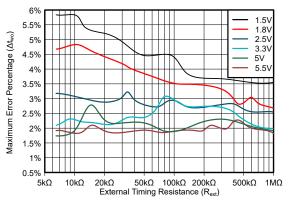
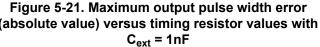


Figure 5-19. Maximum output pulse width error (absolute value) across supply voltage Each line: one timing component combination Shaded area: all timing component combinations



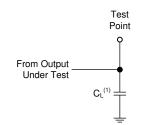




### **6** Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily for the examples listed in the following table. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1MHz, Z<sub>0</sub> = 50 $\Omega$ , t<sub>t</sub> < 2.5ns.

The outputs are measured individually with one input transition per measurement.



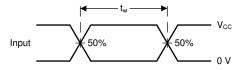
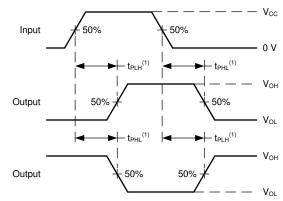


Figure 6-2. Voltage Waveforms, Pulse Duration



(1) The greater between  $t_{PLH}$  and  $t_{PHL}$  is the same as  $t_{pd}$ .

#### Figure 6-4. Voltage Waveforms Propagation Delays

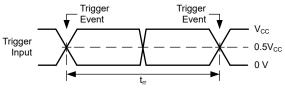


Figure 6-6. Voltage Waveforms, Retrigger Time

(1) C<sub>L</sub> includes probe and test-fixture capacitance.



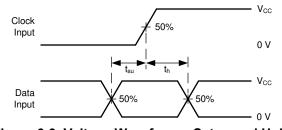
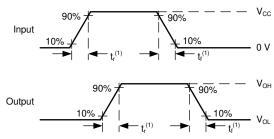
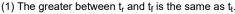


Figure 6-3. Voltage Waveforms, Setup and Hold Times









### 7 Detailed Description

### 7.1 Overview

The TPUL2G123-Q1 device contains two independent retriggerable monostable multivibrator circuits. A monostable multivibrator, also commonly known as a "one shot," produces a single digital pulse when triggered and otherwise maintains a constant output state.

The TPUL2G123-Q1 device features three gated trigger inputs for each channel. For a rising edge trigger, the T or  $\overline{\text{CLR}}$  input is used. For a falling edge trigger the T input is used.

The TPUL2G123-Q1 device includes an asynchronous clear input (CLR) that can be used to terminate an ongoing output pulse.

When triggered, the TPUL2G123-Q1 outputs a positive digital pulse with pulse width defined as  $t_{wo} = K \times R_{ext} \times C_{ext}$ , with  $R_{ext}$  and  $C_{ext}$  being the external timing resistor and external timing capacitor component values measured in  $\Omega$  and F, respectively, and K being a unitless nonlinearity correction factor provided in the *Typical Characteristics* section. The external timing components must be connected as shown in Figure 7-1. The external ground connection to the C terminal is optional.

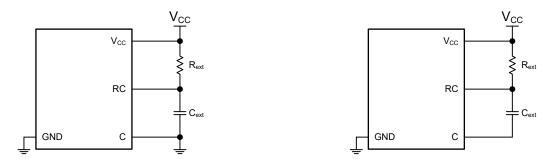


Figure 7-1. Timing component connection, with and without external ground

#### 7.1.1 State Machine Description

The TPUL2G123-Q1 contains a simple state machine as shown in the Figure 7-2 with only three states: ready, discharge, monitor.

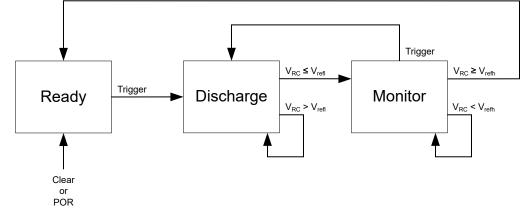


Figure 7-2. State Machine Diagram

In the *ready* state, the TPUL2G123-Q1 shorts the RC pin to V<sub>CC</sub> and holds the digital output inactive.

When triggered, the state machine changes to the *discharge* state. The digital output is immediately set to active and the device internally shorts the RC pin to ground, discharging the external timing capacitor.

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The state machine changes from the *discharge* state to the *monitor* state when the RC pin reaches the low reference voltage ( $V_{refl} = 0.25V_{CC}$ ). The RC pin is then set to high impedance, allowing the external timing circuit to naturally charge the timing capacitor back to  $V_{CC}$ . When the RC voltage reaches the high reference voltage ( $V_{refh} = 0.69V_{CC}$ ), the state machine returns to the *ready* state.

State Name	Inputs	Outputs <sup>(1)</sup>					
State Name	Trigger	V <sub>RC</sub> ≤ V <sub>refl</sub>	V <sub>RC</sub> ≥ V <sub>refh</sub>	CLR	RC	Q	Q
Ready	Discharge	Ready	Ready	Ready	Н	L	Н
Discharge	Discharge	Monitor	Discharge	Ready	L	Н	L
Monitor	Discharge	Monitor	Ready	Ready	Z	Н	L

#### Table 7-1. State Descriptions

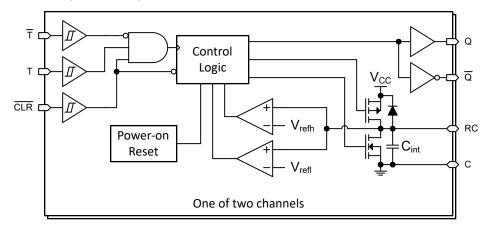
(1) H = Driving high, L = Driving low, Z = High impedance

### 7.2 Functional Block Diagram

 $V_{refh} = 0.69 \times V_{CC}$ 

 $V_{refl} = 0.25 \times V_{CC}$ 

C<sub>int</sub> indicates total internal parasitic capacitance and can be found in the *Electrical Characteristics* table.



### 7.3 Feature Description

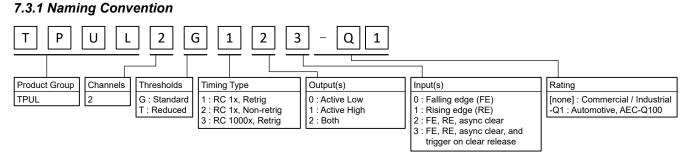


Figure 7-3. Device name meaning

#### 7.3.2 Retriggerable One-Shot

This device includes a retriggerable monostable multivibrator (one-shot) circuit that produces a fixed-width output pulse. The output pulse width for a retriggerable one-shot is extended by additional input triggers while the output is active. The output pulse will expire after the configured time period if no other triggers have been received.

The output pulse width after a retrigger event is always shorter than the normal output pulse width because the timing capacitor does not need to be fully discharged for a retrigger event. The maximum error due to this change is the time to discharge the selected timing capacitor. The error due to retrigger timing can be minimized by selecting larger resistor values and smaller capacitor values for a given pulse width. See retrigger plots in the *Typical Characteristics* section for more details.

#### 7.3.3 Timing Mechanism and Accuracy

The output pulse width ( $t_{wo}$ ) is controlled by the selection of external timing components  $R_{ext}$  and  $C_{ext}$ . The TPUL2G123-Q1 has been designed to target a typical output pulse width of  $t_{wo} \cong R_{ext} \times C_{ext}$ , however the actual pulse width changes with multiple variables, and thus a nonlinearity correction factor, K, is added to provide the system designer with a more accurate pulse width estimation. Equation 1 is used to most accurately predict the output pulse width.

$$t_{\rm wo} = K \times R_{ext} \times C_{ext}$$

The output pulse width is dependent on multiple variables:

- External timing components (Rext, Cext)
- Voltage
- Temperature
- Manufacturing and design

The external timing component values directly control the output pulse width, and any variations in component values due to manufacturing, voltage, or temperature will directly impact the output pulse width.

Most resistors maintain very consistent values during operation, and thus tend to have little impact on accuracy.

Most capacitors have a wide variation of manufacturing values, and additionally can vary due to temperature and operating voltage. Typically, the timing capacitor is the largest single source of error for RC timed monostable multivibrators.

There is also some error introduced by the TPUL2G123-Q1. This error is provided as  $\Delta t_{wo}$  in the *Switching Characteristics* section and includes variations due to design, manufacturing, and temperature.

Estimating the percent error of the output pulse width ( $e_{\Delta two}$ ) requires multiple inputs. Equation 2 provides the best method to estimate total pulse width error due to tolerance of components, with  $e_R$  being the error introduced by the timing resistor,  $e_C$  being the error introduced by the timing capacitor, and  $\Delta t_{wo}$  being the error

**ADVANCE INFORMATION** 

introduced by the TPUL2G123-Q1. There is additionally some randomness inherent to the pulse width even with all other factors held constant which is typically less than 1% and is accounted for in the  $\Delta t_{wo}$  specification.

$$e_{\Delta t w o} = e_R + e_C + e_R e_C + \Delta t_{wo} (1 + e_R + e_C + e_R e_C)$$
<sup>(2)</sup>

For a quick estimate, the sum of the error values can be used ( $e_{\Delta two} \cong e_R + e_C + \Delta t_{wo}$ ). For example, a typical TPUL2G123-Q1 application circuit using an X7R capacitor (5% manufacturing tolerance + 15% temperature variation), 0.1% resistor, and  $\Delta t_{wo}$  of 5% would have a quickly estimated maximum error of 25.1%. With the more accurate equation, the maximum error is actually 26.126%.

#### 7.3.4 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads, so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important to limit the output power of the device to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs must be left disconnected.

### 7.3.5 CMOS Schmitt-Trigger Inputs

This device includes inputs with the Schmitt-trigger architecture. These inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics* table from the input to ground. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings* table, and the maximum input leakage current, given in the *Electrical Characteristics* table, using Ohm's law ( $R = V \div I$ ).

The Schmitt-trigger input architecture provides hysteresis as defined by  $\Delta V_T$  in the *Electrical Characteristics* table, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs with slow transitioning signals will increase dynamic current consumption of the device with the maximum value per input defined as  $\Delta I_{CC}$  in the *Electrical Characteristics* table. For additional information regarding Schmitt-trigger inputs, please see *Understanding Schmitt Triggers*.

Do not leave inputs floating at any time during operation. Unused inputs must be terminated at a valid high or low voltage level. If a system is not actively driving an input at all times, then a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; however, a  $10k\Omega$  resistor is recommended and will typically meet all requirements.

### 7.3.6 Latching Logic with Known Power-Up State

This device includes latching logic circuitry. Latching circuits commonly include D-type latches and D-type flip-flops, but include all logic circuits that act as volatile memory. In typical logic devices, the output state of each latching circuit is unknown after power is initially applied; however, this device includes an added Power On Reset (POR) circuit which sets the states of all included latching circuits during the power-up ramp prior to the device starting normal functionality.

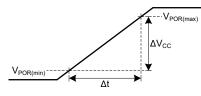


Figure 7-4. Supply (V<sub>CC</sub>) Ramp Characteristics for Known Power-Up State

Figure 7-4 shows a correct supply voltage turn-on ramp and defines values used in the *Recommended Operating Conditions* and *Electrical Characteristics* tables.



Prior to starting the power-on ramp, the supply must be completely off ( $V_{CC} \le V_{POR(min)}$ ).

The supply voltage must ramp at a rate within the range provided in the *Recommended Operating Conditions* table.

The output state of each latching logic circuit only remains stable as long as power is applied to the device ( $V_{CC} \ge V_{POR(max)}$ ).

Variation from these recommendations will result in the device having an unknown power-up state.

#### 7.3.7 Partial Power Down (Ioff)

This device includes circuitry to disable all outputs when the supply pin is held at 0V. When disabled, the outputs will neither source nor sink current, regardless of the input voltages applied. The amount of leakage current at each output is defined by the I<sub>off</sub> specification in the *Electrical Characteristics* table.

#### 7.3.8 Clamp Diode Structure

Figure 7-5 shows the inputs and outputs to this device have negative clamping diodes only.

# **CAUTION** Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

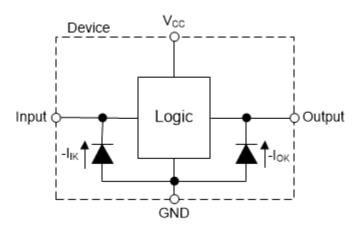


Figure 7-5. Electrical Placement of Clamping Diodes for Each Input and Output



#### 7.4 Device Functional Modes

#### 7.4.1 Off-State Operation

The TPUL2G123-Q1 includes partial-power-down (I<sub>off</sub>) protection, which forces the outputs into a highimpedance state when the supply voltage is approximately 0V. In the powered-off state, voltages can be applied to the digital inputs and outputs and the device will not respond or have any back-powering. This protection does not apply to the RC pin.

#### 7.4.2 Startup Operation

The TPUL2G123-Q1 includes an internal power-on reset (POR) circuit that prevents erroneous triggers from occurring during startup. There are details on the supply ramp requirements provided in *Latching Logic with Known Power-Up State*. Normal operation can be started after the startup time (t<sub>startup</sub>) has expired per the *Timing Requirements* table. While active, the POR circuit holds the TPUL2G123-Q1 in the *Ready* state.

#### 7.4.3 On-State Operation

The table below lists the on-state functional modes for the TPUL2G123-Q1.

	INPUTS <sup>(1)</sup>		OUTPUTS <sup>(2)</sup>								
CLR	T	т	Q	Q							
L	Х	Х	L	Н							
Н	Н	Х	L <sup>(3)</sup>	H <sup>(3)</sup>							
Н	Х	L	L <sup>(3)</sup>	H <sup>(3)</sup>							
Н	L	↑	(4)	(4)							
Н	Ļ	Н	(4)	(4)							
↑ (	L	Н									

#### Table 7-2. Function Table

(1) H = high voltage level, L = low voltage level, X = don't care

(3) These outputs are based on the assumption that the indicated steady-state conditions at the inputs have been set up long enough to complete any output pulse.

(4) If an output pulse is triggered while a previous output pulse is still active, the output continues to drive high for one additional pulse width.



### 8 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

#### 8.1 Application Information

The TPUL2G123-Q1 is used to generate a fixed-width pulse from an input trigger event. This device is retriggerable, meaning that input triggers received while the output is active will cause the output pulse to extend and it will not expire until one configured time period after the most recent trigger.

The input trigger event comes from three gated inputs:  $\overline{T}$ , T, and  $\overline{CLR}$ . These inputs are combined in a 3-input AND gate, with  $\overline{T}$  internally inverted such that the logic follows the boolean equation  $Y = !(\overline{T}) \cdot T \cdot \overline{CLR}$ . Each input has a Schmitt-trigger architecture, and thus includes hysteresis allowing for slow transitioning or noisy signals. An input signal is detected as a logic high if the signal is larger than  $V_{T+}$ , and a low if the input signal is smaller than  $V_{T-}$ . Between  $V_{T+}$  and  $V_{T-}$ , the input signal is detected as the last valid state until one of those values is crossed. An output pulse is triggered on the rising edge of the aforementioned internal Y signal.

The output pulse width is controlled by the selection of external timing components  $R_{ext}$  and  $C_{ext}$ . Plots are provided in the *Typical Characteristics* section to easily select appropriate component values for a desired pulse width. See the *Features* section for additional information regarding the impact of external components on the timing accuracy of the TPUL2G123-Q1.

#### 8.2 Typical Application - Edge Detector

In this application, the TPUL2G123-Q1 is used to detect rising or falling edges on an input signal, producing short pulses at the output for each edge detected. The circuit configuration for a rising edge detector is shown in Figure 8-1. For a falling edge detector, connect the input signal to the  $\overline{T}$  input instead of the T input, and connect the T input to V<sub>CC</sub>. Otherwise, the components and configuration are identical.

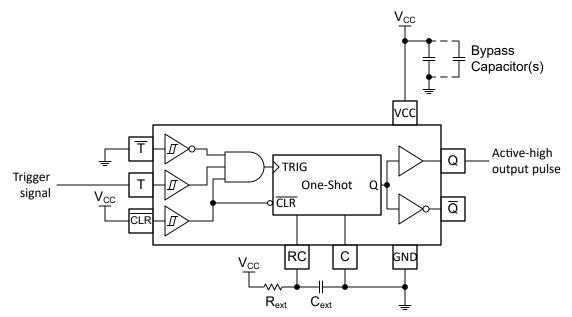


Figure 8-1. Pulse generator schematic using the TPUL2G123-Q1



#### 8.2.1 Design Requirements

#### 8.2.1.1 Timing Components

The external timing components directly determine the output pulse width of the TPUL2G123-Q1.

The range of supported values for R<sub>ext</sub> and C<sub>ext</sub> are provided in the *Recommended Operating Conditions* table. Do not exceed the limits provided in the *Absolute Maximum Ratings* table.

The TPUL2G123-Q1 can be used with no external capacitor, which is described as  $C_{ext} = 0pF$ . In this condition, the output pulse width is determined by the operating voltage and external timing resistor,  $R_{ext}$ , only. The expected variation is provided in the *Switching Characteristics* table for the case of  $R_{ext} = 10k\Omega$ ,  $C_{ext} = 0pF$ .

If an external timing capacitor larger than  $1\mu$ F is used, add an external Schottky diode ( $D_{ext}$ ) as shown in Figure 8-2 to provide an alternate discharge path for the capacitor during power down.

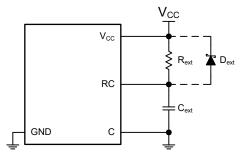


Figure 8-2. External protection diode connection

#### 8.2.1.2 Input Considerations

Input signals must cross  $V_{t-(min)}$  to be considered a logic LOW, and  $V_{t+(max)}$  to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either  $V_{CC}$  or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the TPUL2G123-Q1 (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10k $\Omega$  resistor value is recommended for most applications.

The TPUL2G123-Q1 has no input signal transition rate requirements because it has Schmitt-Trigger inputs, however it is characterized for operation within the limits provided in the *Recommended Operating Conditions* table.

Schmitt-Trigger inputs also provide significant noise rejection, however noise with a large enough amplitude can still cause issues. Refer to the hysteresis value,  $\Delta V_{T(min)}$  in the *Electrical Characteristics*, which will provide the peak-to-peak noise rejection limit.

Unlike what happens with standard CMOS inputs, Schmitt-Trigger inputs can be held at any valid voltage value without causing dangerously large increases in power consumption. The maximum additional current caused by holding an input at a value other than  $V_{CC}$  or ground is provided as  $\Delta I_{CC}$  in the *Electrical Characteristics* table.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.



#### 8.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH-state voltage. Drawing current from the output decreases the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW-state voltage. Sinking current into the output increases the output voltage as specified by the  $V_{OL}$  specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together to avoid excessive current and damage to the device.

The TPUL2G123-Q1 can directly drive a load with a total capacitance less than or equal to 50pF while still meeting all of the data sheet specifications. For larger capacitive loads, add a series resistor to maintain current within the *Absolute Maximum Ratings*.

The TPUL2G123-Q1 can drive a load with total resistance described by  $R_L \ge V_O / I_O$ , with the output voltage and current defined in the *Electrical Characteristics* table with  $V_{OH}$  and  $V_{OL}$ . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V<sub>CC</sub> pin.

Unused outputs can be left floating. Do not connect outputs directly to  $V_{CC}$  or ground.

Refer to the *Feature Description* section for additional information regarding the outputs for this device.

#### 8.2.1.4 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the electrical characteristics of the device as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the TPUL2G123-Q1 plus the maximum static supply current,  $I_{CC}$ , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current as is provided by the positive supply source. Ensure the maximum total current through  $V_{CC}$  listed in the *Absolute Maximum Ratings* is not exceeded. After the output pulse is complete, the external capacitor is quickly recharged to  $V_{CC}$  using the supply with maximum current draw as described by  $I_{Cext(max)}$  in the *Electrical Characteristics*. Additionally, the external timing circuitry will draw power from the supply with a maximum current draw of  $I_{ext(max)} = V_{CC} / R_{ext}$ , which is pulled directly from the supply and thus is not part of the  $I_{CC}$  value for the TPUL2G123-Q1. The dynamic power consumption from the external circuit can be estimated by  $P_{RC} = C_{ext} V_{CC}^2 / t_{wo}$ .

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the TPUL2G123-Q1 plus the maximum supply current,  $I_{CC}$ , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Ensure the maximum total current through GND listed in the *Absolute Maximum Ratings* is not exceeded.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

#### CAUTION

The maximum junction temperature,  $T_{J(max)}$  listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.



#### 8.2.2 Detailed Design Procedure

Texas Instruments provides an Excel-based calculator for getting the best results when using the TPUL2G123-Q1. This calculator can be found through the device's product folder, located in the *Design and development* section. The steps below are used for manually calculating the required timing component values using the information available in this document.

- 1. Select the desired output pulse width, which will be referred to as  $t_{wo}$ .
- 2. Solve:  $C_{ext1} = t_{wo}/50000$ .
- 3. Select the nearest decade capacitor value to C<sub>ext1</sub> from the following and use for C<sub>ext</sub>. { 100pF, 1nF, 10nF, 100nF, 1µF, 10µF }
- 4. Solve:  $R_{ext1} = t_{wo}/C_{ext}$ .
- 5. Using R<sub>ext1</sub> from step 4 and C<sub>ext</sub> from step 3, find the closest K factor using the appropriate plot from the *Typical Characteristics* section.
- 6. Solve:  $R_{ext} = t_{wo}/(K \times C_{ext})$
- 7. Connect the selected timing resistor,  $R_{ext}$ , from RC to  $V_{CC}$ .
- 8. Connect the selected timing capacitor, C<sub>ext</sub>, from RC (positive) to C (negative). The C pin can additionally be connected to ground, however it is not required for normal operation.
- Add a 0.1µF bypass capacitor from V<sub>CC</sub> to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V<sub>CC</sub> and GND pins. An example layout is shown in the *Layout* section.
- 10. Ensure the capacitive load at the output is ≤ 50pF. This is not a hard limit, however, it will optimize performance and prevent reliability issues. This can be accomplished by providing short, appropriately sized traces from the TPUL2G123-Q1 to any receiving devices.
- 11. Ensure the resistive load at the output is larger than (V<sub>CC</sub> / I<sub>O(max)</sub>)Ω. Doing this will prevent the maximum output current from the Absolute Maximum Ratings from being violated. Most CMOS inputs have a resistive load measured in MΩ; much larger than the minimum calculated previously.
- 12. Thermal issues are rarely a concern for TPUL family devices, however, the power consumption and thermal increase can be calculated using the steps provided in the application report, *CMOS Power Consumption and Cpd Calculation*.

### 8.2.3 Application Curves

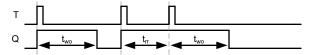


Figure 8-3. Output Pulse Timing Diagram



#### 8.3 Typical Application - Delayed Pulse Generator

In this application, the TPUL2G123-Q1 is used to produce a delayed output pulse from a rising edge input trigger. The circuit configuration is shown in Figure 8-4.

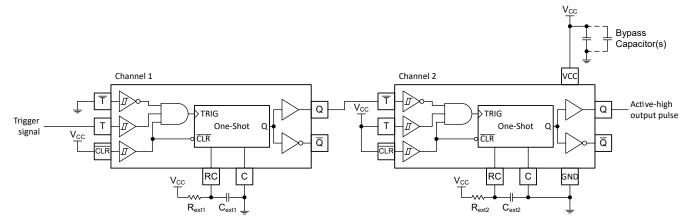


Figure 8-4. Delayed pulse generation schematic using the TPUL2G123-Q1

8.3.1 Application Curves

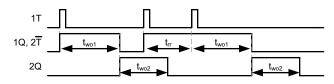


Figure 8-5. Output Pulse Timing Diagram

#### 8.4 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating listed in the *Recommended Operating Conditions*.

During startup, the power supply should ramp within the provided power-up ramp rate range in the *Recommended Operating Conditions* table.

Each V<sub>CC</sub> terminal must have a good bypass capacitor to prevent power disturbance. For normal operation of the TPUL2G123-Q1, a  $0.1\mu$ F bypass capacitor is recommended. To reject different frequencies of noise, use multiple bypass capacitors in parallel. Capacitors with values of  $0.1\mu$ F and  $1\mu$ F are commonly used in parallel.

TPUL2G123-Q1 SCASE78 – APRIL 2025



### 8.5 Layout

#### 8.5.1 Layout Guidelines

- Timing component placement
  - Place near the device
  - Provide an electrically short path to the device terminal connections
- Bypass capacitor placement
- Place near the positive supply terminal of the device
- Provide an electrically short ground return path
- Use wide traces to minimize impedance
- Keep the device, capacitors, and traces on the same side of the board whenever possible
- Signal trace geometry
  - 8mil to 12mil trace width
  - Lengths less than 12cm to minimize transmission line effects
  - Avoid 90° corners for signal traces
  - Use an unbroken ground plane below signal traces
  - Flood fill areas around signal traces with ground
  - For traces longer than 12cm
    - Use impedance controlled traces
    - Source-terminate using a series damping resistor near the output
    - Avoid branches; buffer signals that must branch separately

### 8.5.2 Layout Example

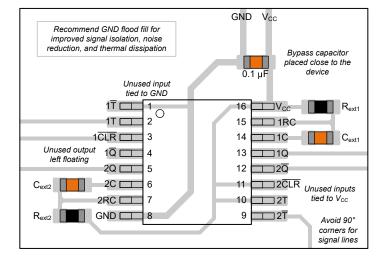


Figure 8-6. Layout Example for TPUL2G123-Q1 in the PW (TSSOP) package



### 9 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

#### 9.1 Documentation Support

#### 9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, CMOS Power Consumption and C<sub>pd</sub> Calculation application report
- Texas Instruments, Designing With Logic application report
- Texas Instruments, Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices application report

#### 9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### **9.3 Support Resources**

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 9.4 Trademarks

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

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#### 9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 9.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

### **10 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
April 2025	*	Advance Information Release

### 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



### 11.1 Packaging Option Addendum

#### **Packaging Information**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish <sup>(4)</sup>	MSL Peak Temp (3)	Op Temp (°C)	Device Marking <sup>(5)</sup> (6)
PTPUL2G123PWRQ 1	PREVIEW	PW	TSSOP	16	3000	RoHS & Green		LEVEL1-260CG	-40 to 125	P1

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PRE\_PROD** Unannounced device, not in production, not available for mass market, nor on the web, samples not available. **PREVIEW:** Device has been announced but is not in production. Samples may or may not be available. **OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details. TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

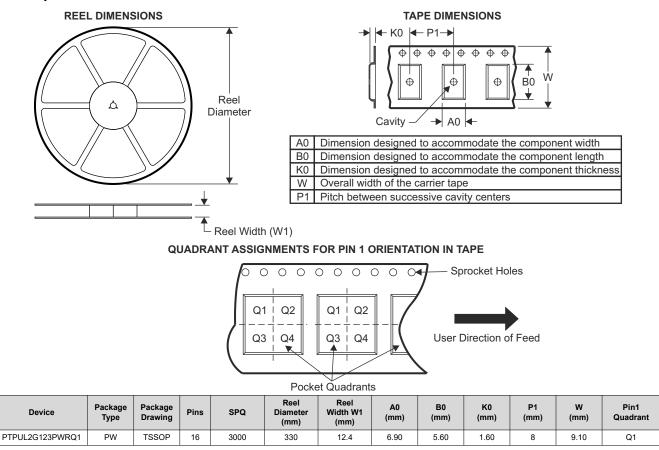
- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device
- (6) Multiple Device markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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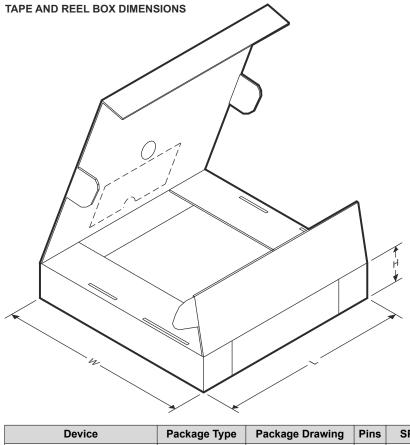
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#### **11.2 Tape and Reel Information**



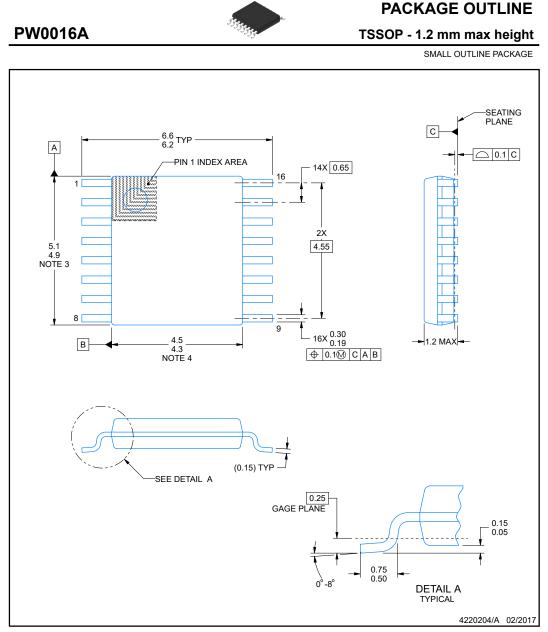




Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
PTPUL2G123PWRQ1	PW	TSSOP	16	3000	353	353	32



#### **11.3 Mechanical Data**



NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing All linear dimensions are in millimeters. Any dimensions in parentnesis are for reference only. Dimensioning and tolera per ASME Y14.5M.
 This drawing is subject to change without notice.
 This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.

- This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
   Reference JEDEC registration MO-153.



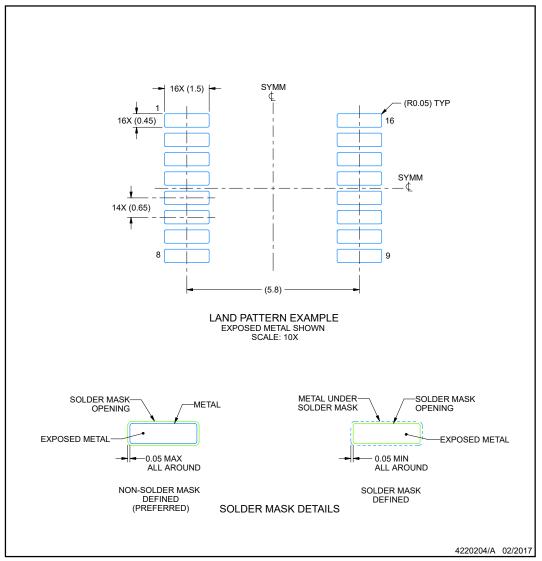


### **EXAMPLE BOARD LAYOUT**

### PW0016A

#### TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

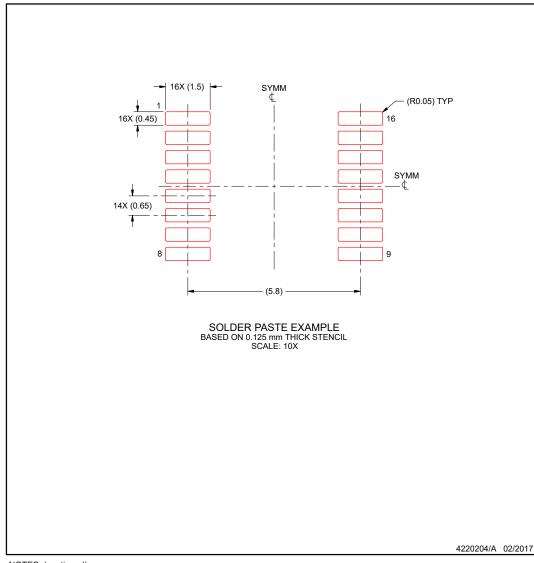




#### **EXAMPLE STENCIL DESIGN**

#### TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations. 9. Board assembly site may have different recommendations for stencil design.





#### **PACKAGING INFORMATION**

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	<b>RoHS</b> (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
PTPUL2G123PWRQ1	Active	Preproduction	TSSOP (PW)   16	3000   LARGE T&R	-	Call TI	Call TI	-40 to 125	
PTPUL2G123PWRQ1.A	Active	Preproduction	TSSOP (PW)   16	3000   LARGE T&R	-	Call TI	Call TI	-40 to 125	

<sup>(1)</sup> **Status:** For more details on status, see our product life cycle.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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#### OTHER QUALIFIED VERSIONS OF TPUL2G123-Q1 :

• Catalog : TPUL2G123



NOTE: Qualified Version Definitions:

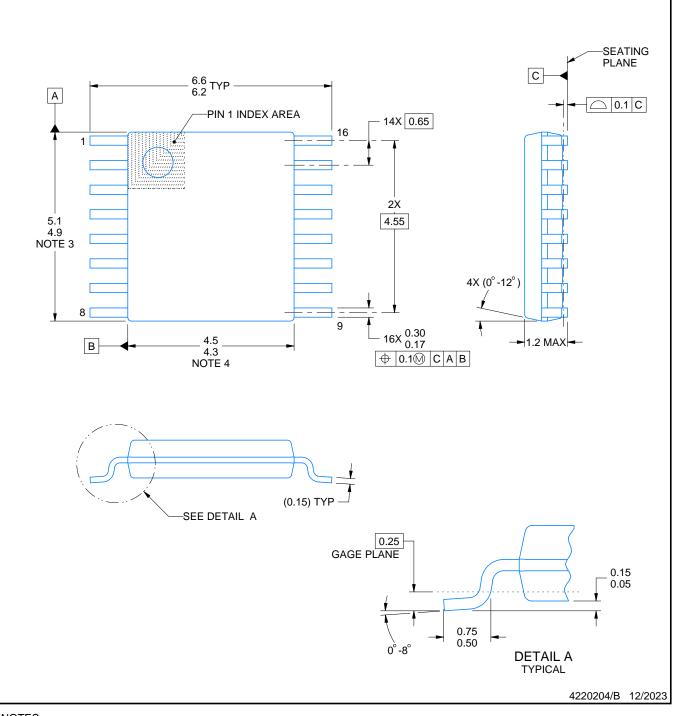
 $_{ullet}$  Catalog - TI's standard catalog product



# **PACKAGE OUTLINE**

### TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

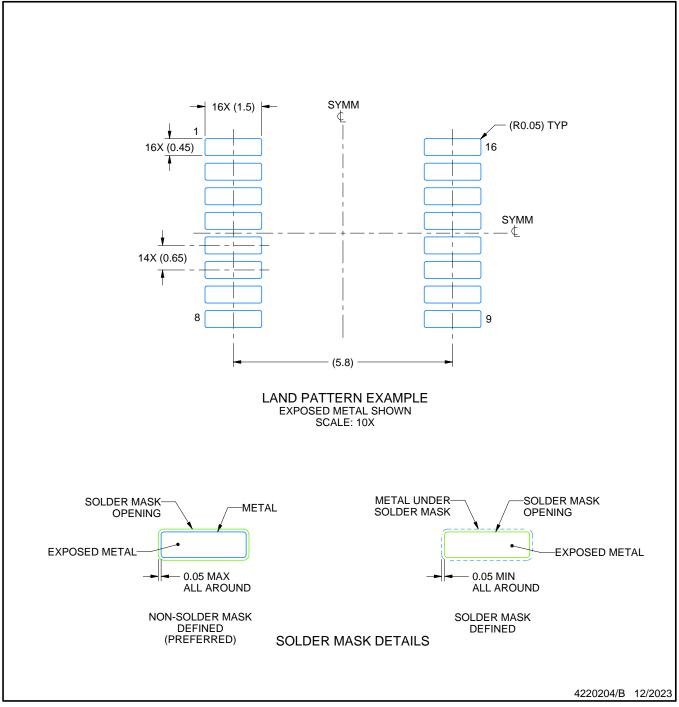
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



# **EXAMPLE BOARD LAYOUT**

### TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

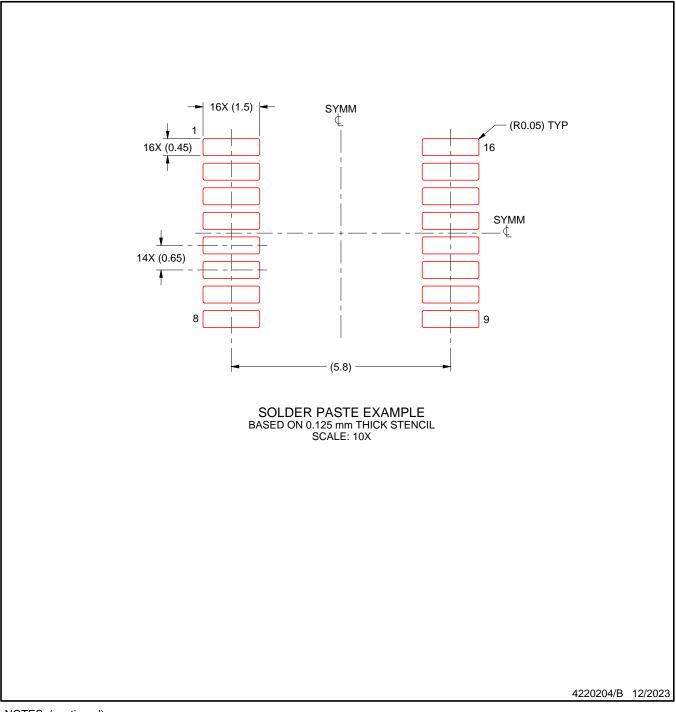
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# **EXAMPLE STENCIL DESIGN**

### TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

9. Board assembly site may have different recommendations for stencil design.



<sup>8.</sup> Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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